Application No.: 10/626,526 Docket No.: SON-2790

AMENDMENTS TO THE CLAIMS

Please amend the claims as set forth below in marked-up form. In addition, please cancel rejected claims 1 and 5, the subject matter of which is to be pursued in a separate continuation application.

- 1. (Cancelled)
- 2. (Currently Amended) A semiconductor device comprising:

an emitter layer;

a base layer; and

a collector layer, the sum of a band gap and electron affinity of said emitter layer being larger than the sum of a band gap and electron affinity of said base layer,

wherein said base layer contains Bi; and The semiconductor device according to claim 1, wherein

said base layer contains GaAsBi.

3. (Currently Amended) A semiconductor device comprising:

an emitter layer;

a base layer; and

a collector layer, the sum of a band gap and electron affinity of said emitter layer being larger than the sum of a band gap and electron affinity of said base layer,

wherein said base layer contains Bi; and The semiconductor device according to claim 1, wherein

said base layer contains GaAsBiN.

4. (Currently Amended) A semiconductor device comprising:

an emitter layer;

a base layer; and

a collector layer, the sum of a band gap and electron affinity of said emitter layer being larger than the sum of a band gap and electron affinity of said base layer,

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wherein said base layer contains Bi; and The semiconductor device according to claim 1, wherein

said base layer contains InPBi.

- 5. (Cancelled)
- 6. (Currently Amended) A semiconductor device comprising:

an emitter layer;

a base layer; and

a collector layer, the sum of a band gap and electron affinity of said emitter layer being larger than the sum of a band gap and electron affinity of said base layer,

wherein said base layer contains Bi; and The semiconductor device according to claim 1, wherein

said emitter layer includes at least one selected from the group consisting of GaAs, AlGaAs, InGaP, and InpInP.

7. (Currently Amended) A semiconductor device comprising:

an emitter layer;

a base layer; and

a collector layer, the sum of a band gap and electron affinity of said emitter layer being larger than the sum of a band gap and electron affinity of said base layer,

wherein said base layer contains Bi; and The semiconductor device according to claim 1, wherein

said collector layer includes at least one selected from the group consisting of GaAs, InGaAs, and InP.